

2.5V LVDS, 1:4 CLOCK BUFFER TERABUFFER™ II

IDT5T9304

Description

The IDT5T9304 2.5V differential clock buffer is a user-selectable differential input to four LVDS outputs. The fanout from a differential input to four LVDS outputs reduces loading on the preceding driver and provides an efficient clock distribution network. The IDT5T9304 can act as a translator from a differential HSTL, eHSTL, LVEPECL (2.5V), LVPECL (3.3V), CML, or LVDS input to LVDS outputs. A single-ended 3.3V / 2.5V LVTTTL input can also be used to translate to LVDS outputs. The redundant input capability allows for an asynchronous change-over from a primary clock source to a secondary clock source. Selectable reference inputs are controlled by SEL.

The IDT5T9304 outputs can be asynchronously enabled/disabled. When disabled, the outputs will drive to the value selected by the GL pin. Multiple power and grounds reduce noise.

Applications

- Clock distribution

Pin Assignment

GND	1	24	A2
PD	2	23	$\overline{A2}$
nc	3	22	GND
V _{DD}	4	21	V _{DD}
$\overline{Q1}$	5	20	$\overline{Q3}$
Q1	6	19	Q3
$\overline{Q2}$	7	18	$\overline{Q4}$
Q2	8	17	Q4
V _{DD}	9	16	V _{DD}
SEL	10	15	GL
\overline{G}	11	14	$\overline{A1}$
GND	12	13	A1

24-Lead TSSOP

4.4mm x 7.8mm x 1.0mm package body

G Package

Top View

Features

- Guaranteed low skew: 25ps (typical)
- Very low duty cycle distortion: 250ps (typical)
- High speed propagation delay: 1.7ns (typical)
- Up to 450MHz operation
- Selectable inputs
- Hot insertable and over-voltage tolerant inputs
- 3.3V/2.5V LVTTTL, HSTL eHSTL, LVEPECL (2.5V), LVPECL (3.3V), CML or LVDS input interface
- Selectable differential inputs to four LVDS outputs
- 2.5V V_{DD}
- -40°C to 85°C ambient operating temperature
- Available in TSSOP package

The Preliminary Information presented herein represents a product in pre-production. The noted characteristics are based on initial product characterization and/or qualification. Integrated Device Technology, Incorporated (IDT) reserves the right to change any circuitry or specifications without notice.

Block Diagram

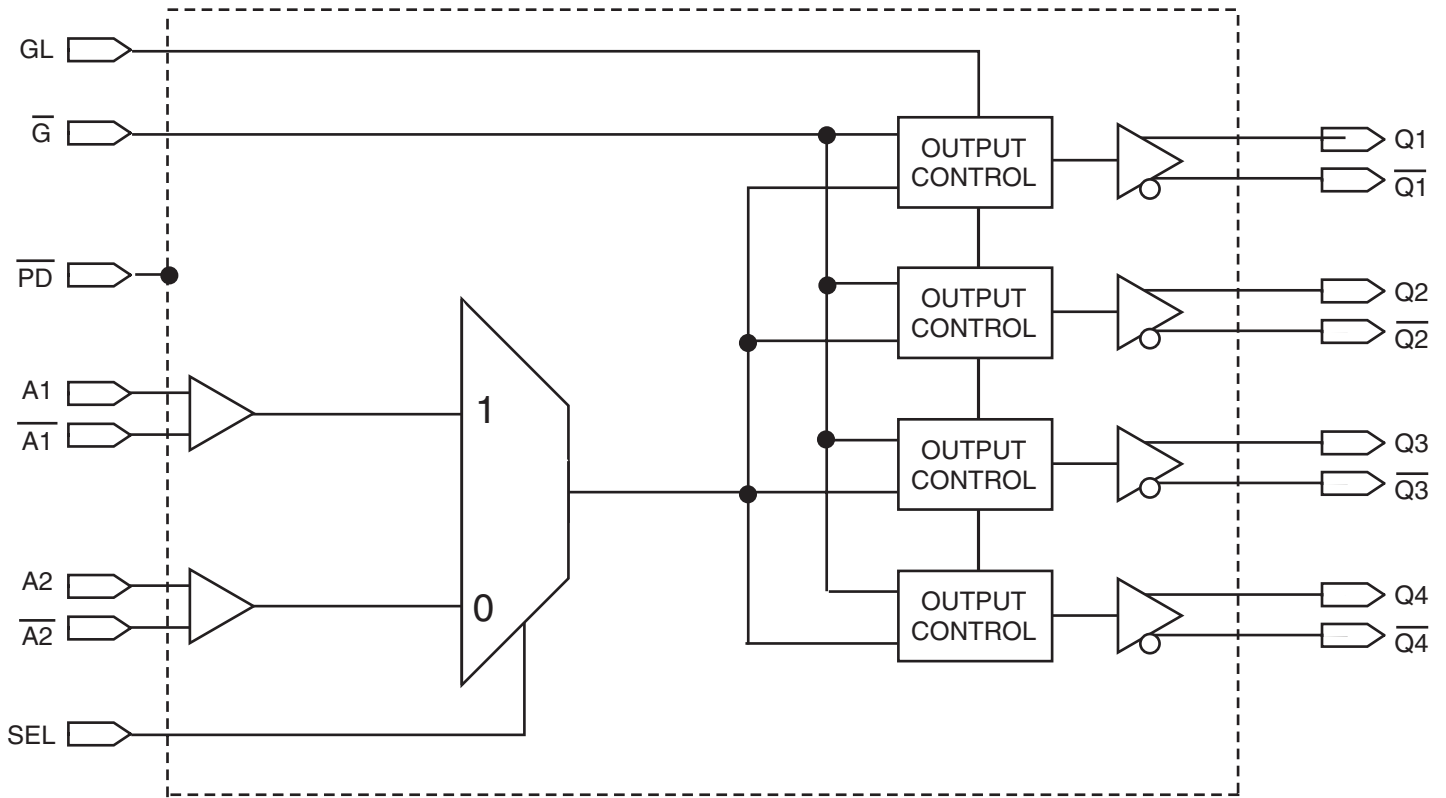


Table 1. Pin Descriptions

Name	Type		Description
A[1:2]	Input	Adjustable ^(1, 4)	Clock input. A[1:2] is the "true" side of the differential clock input.
$\overline{A[1:2]}$	Input	Adjustable ^(1, 4)	Complementary clock inputs. $\overline{A[1:2]}$ is the complementary side of A[1:2]. For LVTTTL single-ended operation, $\overline{A[1:2]}$ should be set to the desired toggle voltage for A[1:2]: 3.3V LVTTTL VREF = 1650mV 2.5V LVTTTL VREF = 1250mV
\overline{G}	Input	LVTTTL	Gate control for differential outputs Q1 and $\overline{Q1}$ through Q4 and $\overline{Q4}$. When \overline{G} is LOW, the differential outputs are active. When \overline{G} is HIGH, the differential outputs are asynchronously driven to the level designated by GL ⁽²⁾ .
GL	Input	LVTTTL	Specifies output disable level. If HIGH, "true" outputs disable HIGH and "complementary" outputs disable LOW. If LOW, "true" outputs disable LOW and "complementary" outputs disable HIGH.
Q[1:4]	Output	LVDS	Clock outputs.
$\overline{Q[1:4]}$	Output	LVDS	Complementary clock outputs.
SEL	Input	LVTTTL	Reference clock select. When LOW, selects A2 and $\overline{A2}$. When HIGH, selects A1 and $\overline{A1}$.
\overline{PD}	Input	LVTTTL	Power-down control. Shuts off entire chip. If LOW, the device goes into low power mode. Inputs and outputs are disabled. Both "true" and "complementary" outputs will pull to VDD. Set HIGH for normal operation. ⁽³⁾
V _{DD}		Power	Power supply for the device core and inputs.
GND		Power	Power supply return for all power.
nc			No connect; recommended to connect to GND.

NOTES:

- Inputs are capable of translating the following interface standards:
Single-ended 3.3V and 2.5V LVTTTL levels
Differential HSTL and eHSTL levels
Differential LVEPECL (2.5V) and LVPECL (3.3V) levels
Differential LVDS levels
Differential CML levels
- Because the gate controls are asynchronous, runt pulses are possible. It is the user's responsibility to either time the gate control signals to minimize the possibility of runt pulses or be able to tolerate them in down stream circuitry.
- It is recommended that the outputs be disabled before entering power-down mode. It is also recommended that the outputs remain disabled until the device completes power-up after asserting PD.
- The user must take precautions with any differential input interface standard being used in order to prevent instability when there is no input signal.

Table 2. Pin Characteristics (T_A = +25°C, F = 1.0MHz)

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C _{IN}	Input Capacitance				3	pF

NOTE: This parameter is measured at characterization but not tested.

Function Tables

Table 3A. Gate Control Output Table

Control Output		Outputs	
GL	\overline{G}	Q[1:4]	$\overline{Q[1:4]}$
0	0	Toggling	Toggling
0	1	LOW	HIGH
1	0	Toggling	Toggling
1	1	HIGH	LOW

Table 3B. Input Selection Table

Selection SEL pin	Inputs
0	A2/A $\overline{2}$
1	A1/A $\overline{1}$

Absolute Maximum Ratings

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability..

Item	Rating
Power Supply Voltage, V_{DD}	-0.5V to +3.6V
Input Voltage, V_I	-0.5V to +3.6V
Output Voltage, V_O Not to exceed 3.6V	-0.5 to $V_{DD} + 0.5V$
Storage Temperature, T_{STG}	-65°C to 150°C
Junction Temperature, T_J	150°C

Recommended Operating Range

Symbol	Description	Minimum	Typical	Maximum	Units
T_A	Ambient Operating Temperature	-40	+25	+85	°C
V_{DD}	Internal Power Supply Voltage	2.3	2.5	2.7	V

DC Electrical Characteristics

Table 4A. LVDS Power Supply DC Characteristics⁽¹⁾, T_A = -40°C to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical ⁽²⁾	Maximum	Units
I _{DDQ}	Quiescent V _{DD} Power Supply Current	V _{DD} = Max., All Input Clocks = LOW ⁽²⁾ ; Output enabled		345		mA
I _{TOT}	Total Power V _{DD} Supply Current	V _{DD} = 2.7V; F _{REFERENCE} Clock = 450MHz		245		mA
I _{PD}	Total Power Down Supply Current	\overline{PD} = LOW		3		mA

NOTE 1: These power consumption characteristics are for all the valid input interfaces and cover the worst case conditions.

NOTE 2: The true input is held LOW and the complementary input is held HIGH.

Table 4B. LVCMOS/LVTTL DC Characteristics⁽¹⁾, T_A = -40°C to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical ⁽²⁾	Maximum	Units
I _{IH}	Input High Current	V _{DD} = = 2.7V			±5	μA
I _{IL}	Input Low Current	V _{DD} = = 2.7V			±5	μA
V _{IK}	Clamp Diode Voltage	V _{DD} = = 2.3V, I _{IN} = -18mA		-0.7	-1.2	V
V _{IN}	DC Input Voltage		-0.3		3.6	V
V _{IH}	DC Input High Voltage		1.7			V
V _{IL}	DC Input Low Voltage				0.7	V
V _{THI}	DC Input Threshold Crossing Voltage			V _{DD} /2		V
V _{REF}	Single-Ended Reference Voltage ⁽³⁾	3.35V LVTTTL		1.65		V
		2.5V LVTTTL		1.25		V

NOTE 1: See *Recommended Operating Range* table.

NOTE 2: Typical values are at V_{DD} = 2.5V, +25°C ambient.

NOTE 3: For A[1:2] single-ended operation, \overline{A} [1:2] is tied to a DC reference voltage.

Table 4C. Differential DC Characteristics⁽¹⁾, T_A = -40°C to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical ⁽²⁾	Maximum	Units
I _{IH}	Input High Current	V _{DD} = = 2.7V			±5	μA
I _{IL}	Input Low Current	V _{DD} = = 2.7V			±5	μA
V _{IK}	Clamp Diode Voltage	V _{DD} = = 2.3V, I _{IN} = -18mA		-0.7	-1.2	V
V _{IN}	DC Input Voltage		-0.3		3.6	V
V _{DIF}	DC Differential Voltage ⁽³⁾		0.1			V
V _{CM}	DC Common Mode Input Voltage		0.05		V _{DD}	V

NOTE 1: See *Recommended Operating Range* table.

NOTE 2: Typical values are at V_{DD} = 2.5V, +25°C ambient.

NOTE 3: V_{DIF} specifies the minimum input differential voltage (V_{TR} - V_{CP}) required for switching where V_{TR} is the "true" input level and V_{CP} is the "complement" input level. The DC differential voltage must be maintained to guarantee retaining the existing HIGH or LOW input. The AC differential voltage must be achieved to guarantee switching to a new state.

NOTE 4: V_{CM} specifies the maximum allowable range of (V_{TR} + V_{CP}) /2.

Table 4D. LVDS DC Characteristics⁽¹⁾, $T_A = -40^{\circ}\text{C}$ to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical ⁽²⁾	Maximum	Units
$V_{OT(+)}$	Differential Output Voltage for the True Binary State		247		454	mV
$V_{OT(-)}$	Differential Output Voltage for the False Binary State		247		454	mV
ΔV_{OT}	Change in V_{OT} Between Complementary Output States				50	mV
V_{OS}	Output Common Mode Voltage (Offset Voltage)		1.125	1.2	1.375	V
ΔV_{OS}	Change in V_{OS} Between Complementary Output States				50	mV
I_{OS}	Outputs Short Circuit Current	V_{OUT+} and $V_{OUT-} = 0V$		12	24	mA
I_{OSD}	Differential Outputs Short Circuit Current	$V_{OUT+} = V_{OUT-}$		6	12	mA

NOTE 1: See *Recommended Operating Range* table.

NOTE 2: Typical values are at $V_{DD} = 2.5V$, $+25^{\circ}\text{C}$ ambient.

AC Electrical Characteristics

Table 5A. HSTL Differential Input AC Characteristics, $T_A = -40^{\circ}\text{C}$ to 85°C

Symbol	Parameter	Value	Units
V_{DIF}	Input Signal Swing ⁽¹⁾	1	V
V_X	Differential Input Signal Crossing Point ⁽²⁾	750	mV
D_H	Duty Cycle	50	%
V_{THI}	Input Timing Measurement Reference Level ⁽³⁾	Crossing Point	V
t_R / t_F	Input Signal Edge Rate ⁽⁴⁾	2	V/ns

NOTE 1. The 1V peak-to-peak input pulse level is specified to allow consistent, repeatable results in an automatic test equipment (ATE) environment. This device meets the V_{DIF} (AC) specification under actual use conditions.

NOTE 2. A 750mV crossing point level is specified to allow consistent, repeatable results in an automatic test equipment (ATE) environment. This device meets the V_X specification under actual use conditions.

NOTE 3. In all cases, input waveform timing is marked at the differential cross-point of the input signals.

NOTE 4. The input signal edge rate of 2V/ns or greater is to be maintained in the 20% to 80% range of the input waveform.

Table 5B. eHSTL AC Differential Input Characteristics, $T_A = -40^\circ\text{C}$ to 85°C

Symbol	Parameter	Value	Units
V_{DIF}	Input Signal Swing ⁽¹⁾	1	V
V_X	Differential Input Signal Crossing Point ⁽²⁾	900	mV
D_H	Duty Cycle	50	%
V_{THI}	Input Timing Measurement Reference Level ⁽³⁾	Crossing Point	V
t_R / t_F	Input Signal Edge Rate ⁽⁴⁾	2	V/ns

NOTE 1. The 1V peak-to-peak input pulse level is specified to allow consistent, repeatable results in an automatic test equipment (ATE) environment. This device meets the V_{DIF} (AC) specification under actual use conditions.

NOTE 2. A 900mV crossing point level is specified to allow consistent, repeatable results in an automatic test equipment (ATE) environment. This device meets the V_X specification under actual use conditions.

NOTE 3. In all cases, input waveform timing is marked at the differential cross-point of the input signals.

NOTE 4. The input signal edge rate of 2V/ns or greater is to be maintained in the 20% to 80% range of the input waveform.

Table 5C. LVEPECL (2.5V) and LVPECL (3.3V) Differential Input AC Characteristics, $T_A = -40^\circ\text{C}$ to 85°C

Symbol	Parameter	Maximum	Units
V_{DIF}	Input Signal Swing ⁽¹⁾	732	mV
V_X	Differential Input Cross Point Voltage ⁽²⁾	LVEPECL	1082
		LVPECL	1880
D_H	Duty Cycle	50	%
V_{THI}	Input Timing Measurement Reference Level ⁽³⁾	Crossing Point	V
t_R / t_F	Input Signal Edge Rate ⁽⁴⁾	2	V/ns

NOTE 1. The 732mV peak-to-peak input pulse level is specified to allow consistent, repeatable results in an automatic test equipment (ATE) environment. This device meets the V_{DIF} (AC) specification under actual use conditions.

NOTE 2. A 1082mV LVEPECL (2.5V) and 1880 LVPECL (3.3V) crossing point level is specified to allow consistent, repeatable results in an automatic test equipment (ATE) environment. This device meets the V_X specification under actual use conditions.

NOTE 3. In all cases, input waveform timing is marked at the differential cross-point of the input signals.

NOTE 4. The input signal edge rate of 2V/ns or greater is to be maintained in the 20% to 80% range of the input waveform.

Table 5D. LVDS Differential Input AC Characteristics, $T_A = -40^\circ\text{C}$ to 85°C

Symbol	Parameter	Maximum	Units
V_{DIF}	Input Signal Swing ⁽¹⁾	400	mV
V_X	Differential Input Cross Point Voltage ⁽²⁾	1.2	V
D_H	Duty Cycle	50	%
V_{THI}	Input Timing Measurement Reference Level ⁽³⁾	Crossing Point	V
t_R / t_F	Input Signal Edge Rate ⁽⁴⁾	2	V/ns

NOTE 1. The 400mV peak-to-peak input pulse level is specified to allow consistent, repeatable results in an automatic test equipment (ATE) environment. This device meets the V_{DIF} (AC) specification under actual use conditions.

NOTE 2. A 1.2V crossing point level is specified to allow consistent, repeatable results in an automatic test equipment (ATE) environment. This device meets the V_X specification under actual use conditions.

NOTE 3. In all cases, input waveform timing is marked at the differential cross-point of the input signals.

NOTE 4. The input signal edge rate of 2V/ns or greater is to be maintained in the 20% to 80% range of the input waveform.

Table 5E. AC Differential Input Characteristics⁽¹⁾, $T_A = -40^\circ\text{C}$ to 85°C

Symbol	Parameter	Minimum	Typical	Maximum	Units
V_{DIF}	AC Differential Voltage ⁽²⁾	0.1		3.6	V
V_X	Differential Input Cross Point Voltage	0.05		V_{DD}	V
V_{CM}	Common Mode Input Voltage Range ⁽³⁾	0.05		V_{DD}	V
V_{IN}	Input Voltage	-0.3		3.6	V/ns

NOTE 1. The output will not change state until the inputs have crossed and the minimum differential voltage range defined by V_{DIF} has been met or exceeded.

NOTE 2. V_{DIF} specifies the minimum input voltage ($V_{TR} - V_{CP}$) required for switching where V_{TR} is the "true" input level and V_{CP} is the "complement" input level. The AC differential voltage must be achieved to guarantee switching to a new state..

NOTE 3. V_{CM} specified the maximum allowable range of $(V_{TR} + V_{CP}) / 2$.

Table 5E. AC Characteristics^(1,5), $T_A = -40^{\circ}\text{C}$ to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$t_{sk(o)}$	Same Device Output Pin-to-Pin Skew ⁽²⁾			25		ps
$t_{sk(p)}$	Pulse Skew ⁽³⁾			250		ps
$t_{sk(pp)}$	Part-to-Part Skew ⁽⁴⁾			TBD		ps
t_{pLH}	Propagation Delay, Low-to-High	A Crosspoint to $Q_n/\overline{Q_n}$ Crosspoint		1.7		ns
t_{pHL}	Propagation Delay, High-to-Low			1.4		ns
f_o	Frequency Range ⁽⁶⁾				450	MHz
t_{PGE}	Output Gate Enable Crossing V_{THI} -to- $Q_n/\overline{Q_n}$ Crosspoint				3.5	ns
t_{PGD}	Output Gate Enable Crossing V_{THI} -to- $Q_n/\overline{Q_n}$ Crosspoint Driven to Designated Level				3.5	ns
t_{PWRDN}	PD Crossing V_{THI} -to- $Q_n = V_{DD}$, $\overline{Q_n} = V_{DD}$				100	μS
t_{PWRUP}	Output Gate Disable Crossing V_{THI} to $Q_n/\overline{Q_n}$ Driven to Designated Level				100	μS

NOTE 1. AC propagation measurements should not be taken within the first 100 cycles of startup.

NOTE 2. Skew measured between crosspoints of all differential output pairs under identical input and output interfaces, transitions and load conditions on any one device.

NOTE 3. Skew measured is the difference between propagation delay times t_{pHL} and t_{pLH} of any differential output pair under identical input and output interfaces, transitions and load conditions on any one device.

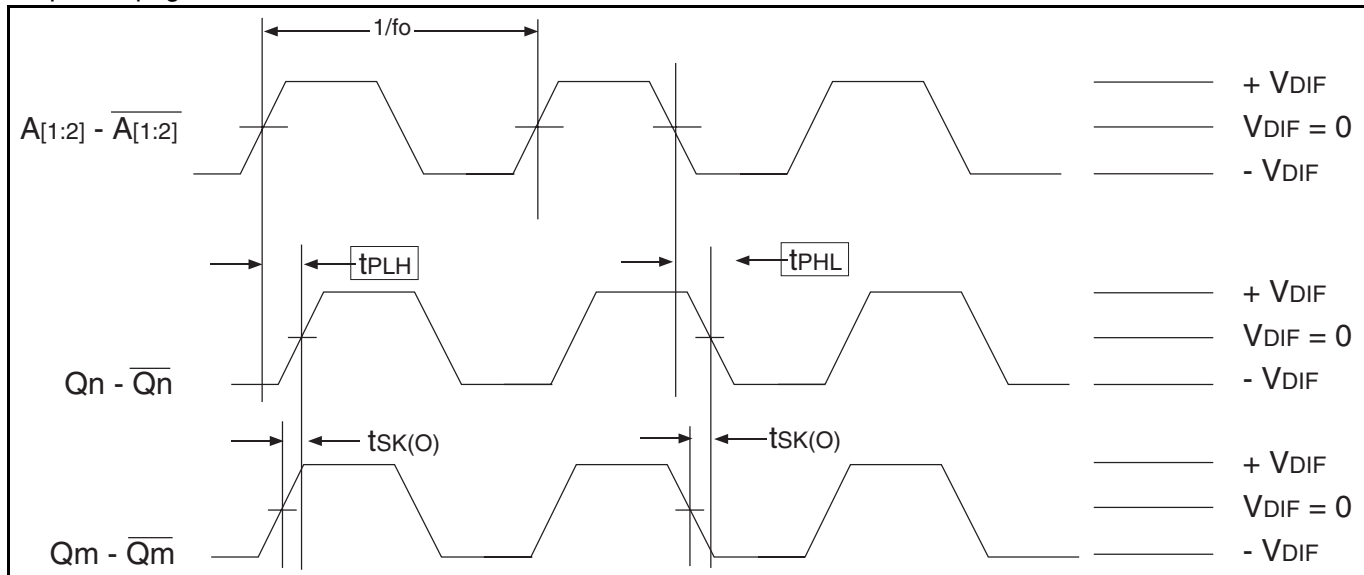
NOTE 4. Skew measured is the magnitude of the difference in propagation times between any single differential output pair of two devices, given identical transitions and load conditions at identical VDD levels and temperature.

NOTE 5. All parameters are tested with a 50% input duty cycle.

NOTE 6. Guaranteed by design but not production tested.

Differential AC Timing Waveforms

Output Propagation and Skew Waveforms



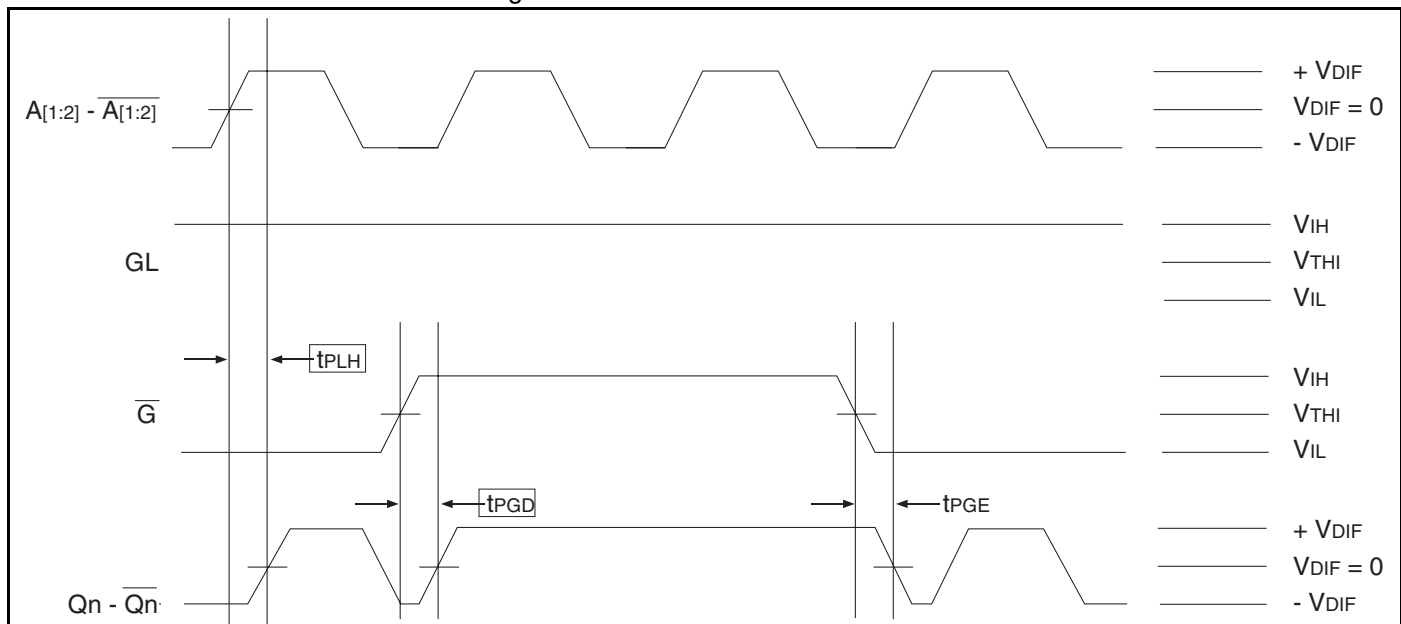
NOTE 1: Pulse skew is calculated using the following expression:

$$t_{sk(p)} = |t_{p_{HL}} - t_{p_{LH}}|$$

Note that the $t_{p_{HL}}$ and $t_{p_{LH}}$ shown above are not valid measurements for this calculation because they are not taken from the same pulse.

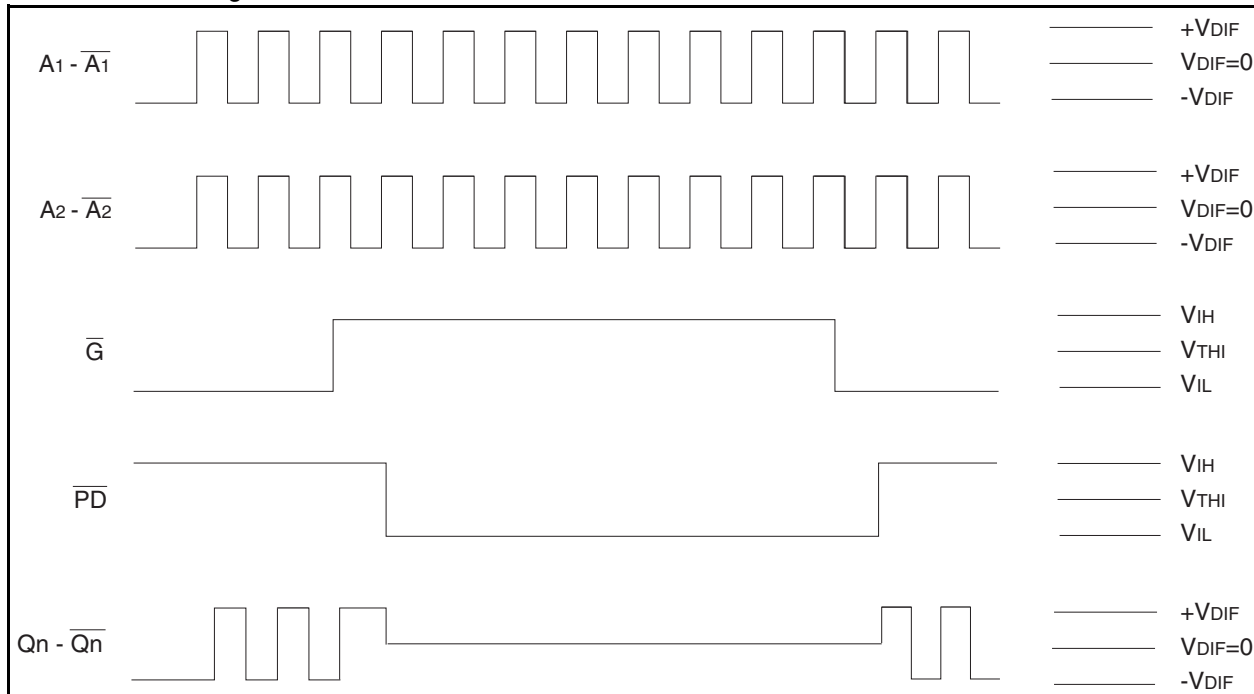
NOTE 2: AC propagation measurements should not be taken within the first 100 cycles of startup.

Differential Gate Disabled/Endable Showing Runt Pulse Generation



NOTE 1: As shown, it is possible to generate runt pulses on gate disable and enable of the outputs. It is the user's responsibility to time the \overline{G} signal to avoid this problem.

Power Down Timing



NOTE 1: It is recommended that outputs be disabled before entering power-down mode. It is also recommended that the outputs remain disabled until the device completes power-up after asserting \overline{PD} .

NOTE 2: The *Power Down Timing* diagram assumes that G_L is HIGH.

NOTE 3: It should be noted that during power-down mode, the outputs are both pulled to V_{DD} . In the *Power Down Timing* diagram this is shown when $Q_n/\overline{Q_n}$ goes to $V_{DIF} = 0$.

Test Circuit for Differential Input

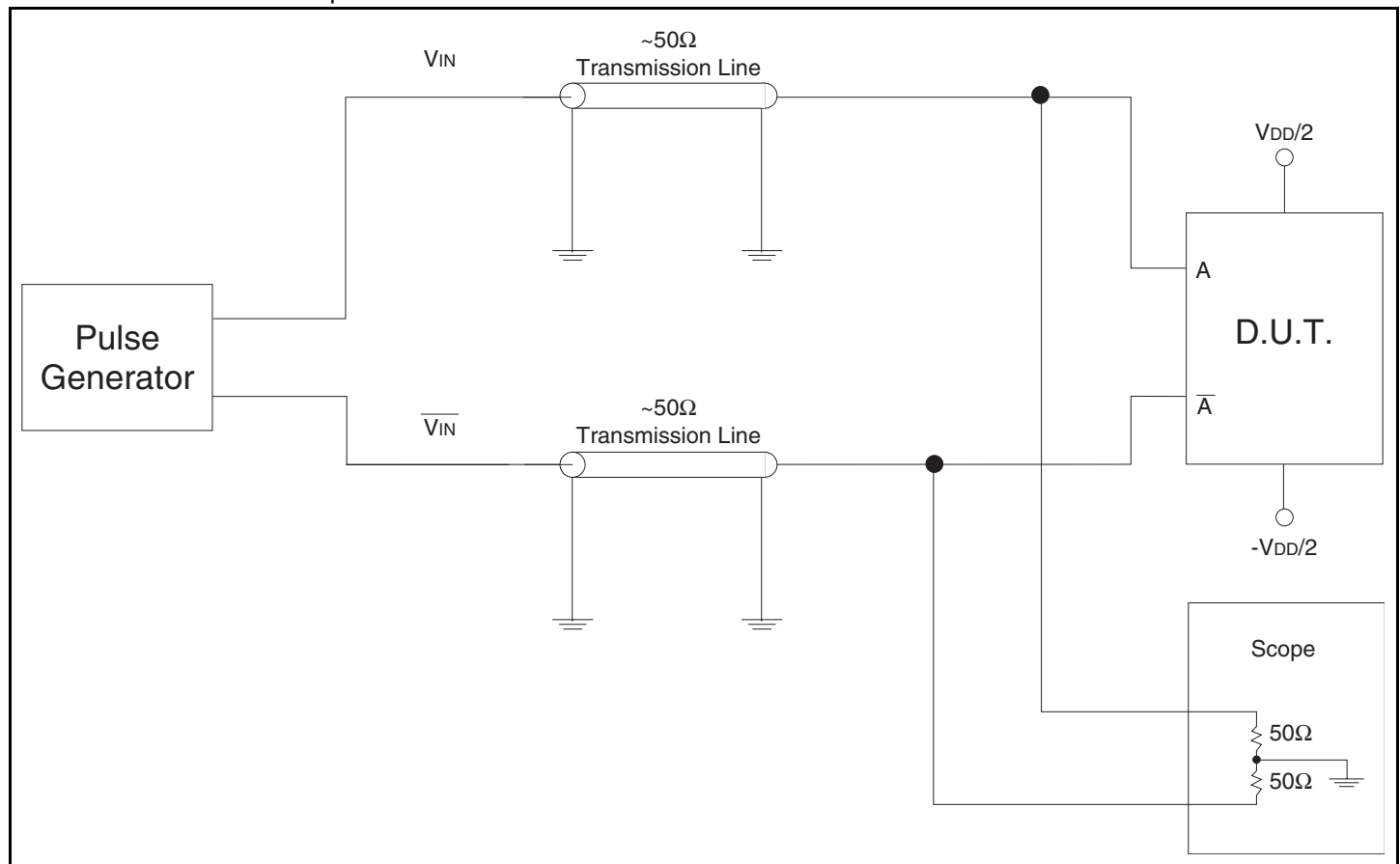
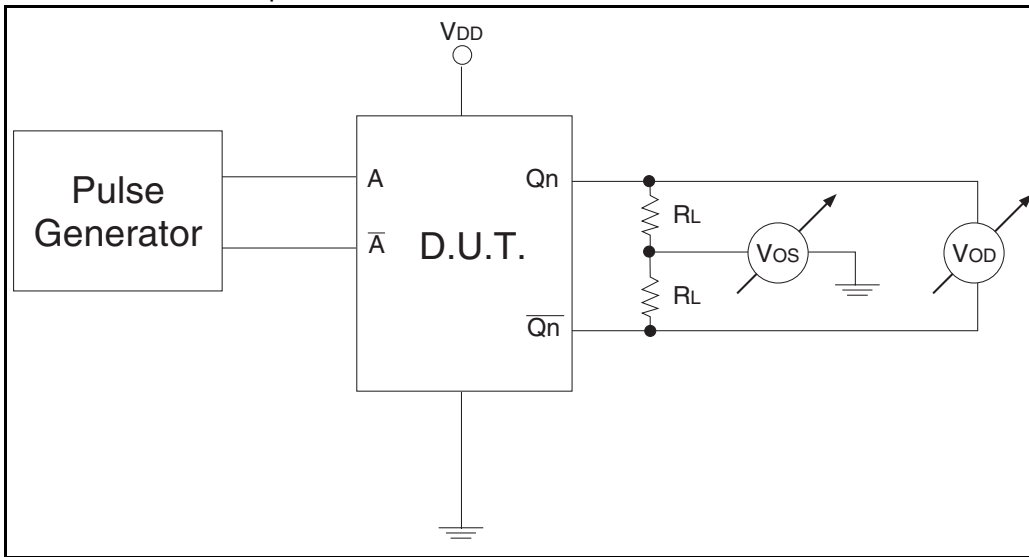


Table 6A. Differential Input Test Conditions

Symbol	$V_{DD} = 2.5V \pm 0.2V$	Unit
V_{THI}	Crossing of A and \overline{A}	V

Test Circuit for DC Outputs and Power Down Tests



Test Circuit for Propagation, Skew, and Gate Enable/Disable Timing

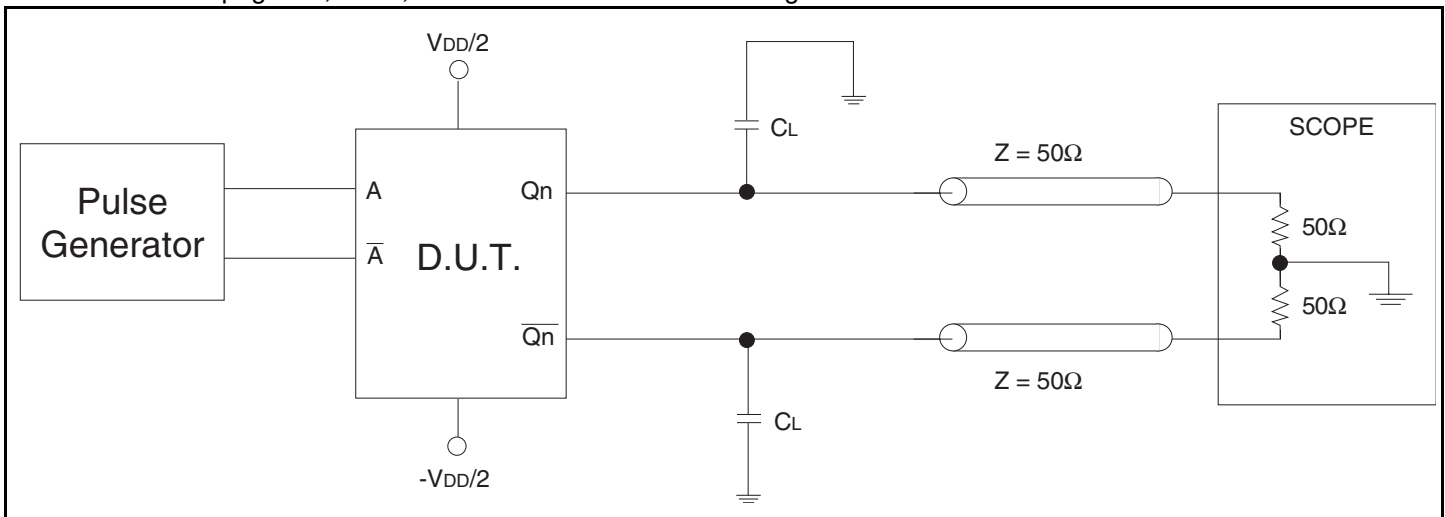


Table 6B. Differential Input Test Conditions

Symbol	$V_{DD} = 2.5V \pm 0.2V$	Unit
C_L	0 ⁽¹⁾	pF
	8 ^(1,2)	pF
R_L	50	Ω

NOTE 1: Specifications only apply to "Normal Operations" test condition. The T_{IA}/E_{IA} specification load is for reference only.

NOTE 2: The scope inputs are assumed to have a 2pF load to ground. $T_{IA}/E_{IA} - 644$ specifies 5pF between the output pair. With $C_L = 8pF$, this gives the test circuit appropriate 5pF equivalent load.

Ordering Information

Table 7. Ordering Information

IDT	XXXXX	XX	X		
	Device Type	Package	Process		
			I		-40°C to +85°C (Industrial)
			PG PGG		Thin Shrink Small Outline Package TSSOP - Green
			5T9304		2.5V LVDS 1:4 Glitchless Clock Buffer Terabuffer™ II

Innovate with IDT and accelerate your future networks. Contact:

www.IDT.com

For Sales

800-345-7015
408-284-8200
Fax: 408-284-2775

For Tech Support

netcom@idt.com
480-763-2056

Corporate Headquarters

Integrated Device Technology, Inc.
6024 Silver Creek Valley Road
San Jose, CA 95138
United States
800 345 7015
+408 284 8200 (outside U.S.)

Asia Pacific and Japan

Integrated Device Technology
Singapore (1997) Pte. Ltd.
Reg. No. 199707558G
435 Orchard Road
#20-03 Wisma Atria
Singapore 238877
+65 6 887 5505

Europe

IDT Europe, Limited
321 Kingston Road
Leatherhead, Surrey
KT22 7TU
England
+44 (0) 1372 363 339
Fax: +44 (0) 1372 378851

